R&S®MXO 4 SERIES OSCILLOSCOPE

Next generation oscilloscope for accelerated insight



Product Brochure Version 04.03

Oscilloscope innovation. Measurement confidence. www.rohde-schwarz.com/product/MXO4

ROHDE&SCHWARZ

Make ideas real



NEXT GENERATION TECHNOLOGY

R&S®MXO 4 SERIES OSCILLOSCOPE

The R&S®MXO 4 series is the first of a new generation of oscilloscopes that excels in both performance and value. The instruments deliver a once-in-a-decade engineering breakthrough for accelerated insight.



A touch above other oscilloscopes in its class, the R&S®MXO 4 series oscilloscope sports an impressive 13.3" Full HD capacitive touchscreen and an intuitive user interface with a learning curve of less than 15 minutes.

WHY ENGINEERS CONTINUE TO UPGRADE TO ROHDE & SCHWARZ OSCILLOSCOPES?

- ► Trusted, global company committed to highest quality standards, long-term customer relationships and technological innovation
- ► Industry's newest oscilloscope portfolio from 60 MHz to 16 GHz
- ► ASIC investments enable world's most responsive oscilloscope
- ► Frontend technology developments offer pristine signal integrity
- ► 16-bit and 18-bit architectures with HD mode provide highest resolution
- ► Digital triggering delivers world's most sensitive event isolation
- Superior user interface and front panel experience

WHY USE THE R&S®MXO 4?

- ► World's first oscilloscope with update rate exceeding 4.5 million waveforms per second
- ► Industry leading 12-bit ADC at all sample rates
- ► Industry best 18-bit architecture
- Fastest and most accurate spectrum analysis in its class
- ► Industry's deepest standard memory of 400 Mpoints per channel
- ► Industry's fastest trigger rearm time of 21 ns
- ► First in class to incorporate new digital triggering technology
- ► Industry's most sensitive trigger of 0.0001 div
- ► Best in class trigger jitter of < 1 ps
- ► First oscilloscope with dual-path protocol analysis
- ► First in class with R&S®SmartGrid user interface

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And there is so much more ...

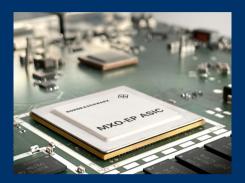
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- 200 MHz to 1.5 GHz bandwidth
- ► Up to 5 Gsample/s sample rate
- 400 Mpoints per channel standard memory
- ▶ 12-bit ADC at all sample rates
- ► 18-bit architecture with HD mode
- Precise digital trigger

CUTTING-EDGE TECHNOLOGY BLOCKS

THAT HELP GIVE YOU ACCELERATED INSIGHT

The R&S®MXO 4 series oscilloscopes utilize advanced technologies to achieve fast and accurate results. Custom technology and innovative features in our oscilloscopes quickly boost your understanding of circuit behaviors.



MXO-EP processing ASIC

See more of your signals, faster

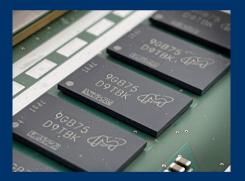
At the heart of each R&S®MXO 4 series oscilloscope is a Rohde&Schwarz developed application-specific integrated circuit (ASIC): MXO-EP (extreme performance). MXO-EP processes 200 Gbit/s to deliver the world's fastest update rate of up to > 4.5 million acquisitions/s. See and capture more of your signals, faster. Find rare signal anomalies quickly. Experience the most responsive oscilloscope in the industry.



12-bit ADC, 18-bit vertical architecture

Measure your signals accurately.

Measurement accuracy is highly dependent on the components in the signal path, e.g. amplifiers, samplers and A/D converters. The workhorse of the R&S®MXO 4 series is an extremely low-noise signal path including a 12-bit ADC. High-definition (HD) mode increases vertical resolution to industry best 18-bit architecture. Get accurate measurements all the time.



Responsive deep memory

Capture more of your signals

R&S®MXO 4 series oscilloscopes come equipped with the industry's deepest standard acquisition memory of 400 Mpoints per channel. Capture up to 80 ms of power up or power down sequences with the highest time resolution of 200 ps. The memory controller in the MXO-EP ASIC ensures the oscilloscope stays responsive with deep memory.



Advanced digital triggering system

Easily isolate subtle signal variations

The MXO-EP ASIC incorporates advanced digital triggering that evaluates the ADC samples in the acquisition path in real time. Trigger on small events of less than 0.0001 vertical division that no other oscilloscope can isolate. Choose your own trigger hysteresis. Apply digital filters to suppress noise to get the most precise triggering available.

FIND SIGNAL ANOMALIES QUICKLY

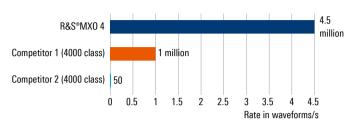
WITH UNPARALLELED UPDATE RATES

- ► World's fastest acquisition rate of up to > 4.5 million waveforms/s reveals infrequent anomalies instantly
- Up to 90 % real-time signal capture and display ensures instant display of all signal details
- ► Signal processing based on MXO-EP ASIC ensures responsive deep memory

World's fastest update rate

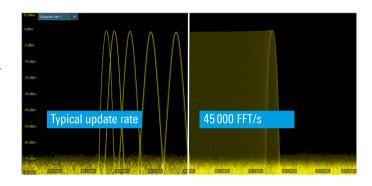
The R&S®MXO 4 oscilloscope processing path contains a dedicated ASIC: the MXO-EP (extreme performance). Thanks to optimized signal processing, the R&S®MXO 4 oscilloscope reaches an exceptional update rate. Its unique architecture allows the R&S®MXO 4 to acquire, process and display up to > 4.5 million waveforms/s.

Real-time acquisition rate



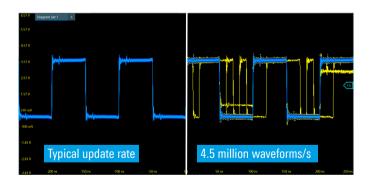
Available with active automatic measurements, FFTs or cursor measurements

The R&S®MXO 4 oscilloscope offers a high update rate even when FFTs, automatic measurements or cursor measurements are active. Also when performing analysis with deep memory acquisitions, the MXO-EP based signal processing path ensures smooth workflows.



Quickly and reliably detect sporadic signal faults

The statistical confidence in results grows with the number of waveforms acquired. A high update rate increases the likelihood of detecting and displaying signal faults and including them in the analysis. Its high update rate enables the R&S®MXO 4 to generate trustworthy statistical results based on a high number of waveforms acquired in a short time. This is crucial for quickly understanding electronic circuits.



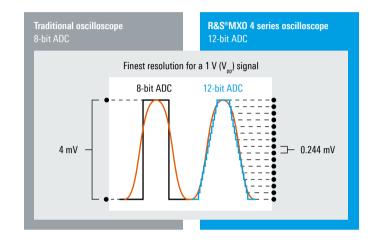
SEE YOUR SIGNALS ACCURATELY

LOWEST MEASUREMENT NOISE AND HIGHEST VERTICAL RESOLUTION

- ▶ 12-bit ADC for high vertical resolution at all sample rates across the full bandwidth
- ► 18-bit architecture with HD mode
- ► Low noise at 50 Ω input impedance (1 mV/div setting)
 - 104 µV (at 1 GHz, 12-bit standard mode)
 - 56 µV (at 500 MHz, 14-bit HD mode)
- ► Vertical scaling down to 500 μV/div at full bandwidth
- ▶ Industry's highest available offset range of ±5 V at 500 µV/div

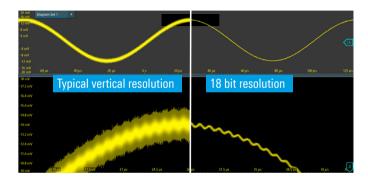
12-bit ADC even at the fastest sample rates

All R&S®MXO 4 series oscilloscopes incorporate a 12-bit ADC. 12 bit vertical resolution delivers 4096 quantization levels for precise vertical sampling. This is a 16-fold improvement over 8-bit ADCs. The ADC stays in 12-bit mode all the time, even at the fastest sample rates.



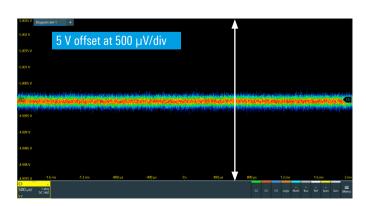
18-bit architecture with HD mode

Offering a user tradeoff between bandwidth and bits of resolution, HD mode, implemented in hardware for fast speed, achieves up to 18 bit vertical resolution. This allows you to see sharper waveforms with more signal details that would otherwise be masked by noise. In addition to superior vertical resolution, the R&S®MXO 4 series oscilloscope is engineered with the lowest-in-industry system measurement noise of just 22 µV AC (RMS) at 1 mV/div.



Vertical sensitivity to 500 µV/div with ±5 V offset range

The R&S°MXO 4 series oscilloscope offers an outstanding sensitivity down to 500 μ V/div without any unexpected reduction in bandwidth. With an offset of ± 5 V at higher sensitivity vertical scale, you can easily place the signal at the center of the screen. A higher offset enables use of more sensitive vertical resolution, meaning a higher number of ADC bits and lower noise.



CAPTURE MORE TIME

DEEPEST STANDARD MEMORY

- ► Industry's deepest memory of 400 Mpoints per channel (optionally 800 Mpoints interleaved)
- Standard segmented memory (10 000 segments, optionally 1 000 000 segments)
- Standard history mode (10 000 acquisitions, optionally 1 000 000 acquisitions)

Deep memory as an insurance policy

After bandwidth and sample rate, memory depth is the most important attribute that determines an oscilloscope's ability to handle a large range of troubleshooting tasks. More acquisition memory gives oscilloscopes the ability to capture more time. More memory enables oscilloscopes to retain the maximum sample rate and bandwidth even with slower timebase settings.

With 400 Mpoints acquisition memory standard on all four channels simultaneously, the R&S®MXO 4 series oscilloscope offers up to 100 times the standard memory compared to the primary competitor.

Maintain fast sample rates with slow timebase settings

Ever adjusted your oscilloscope timebase to capture longer periods of time, pressed stop, then zoomed in to find signal details that do not look right? If so, you have experienced the aliasing problem that oscilloscopes with shallow memory have. The deep memory of the R&S®MXO 4 enables longer time captures at full sample rate.

Standard segmented memory

Use segmented memory to capture signals separated by inactivity. Examples include laser pulses, serial bus activities and RF pulses. The segmented memory of the R&S®MXO 4 series oscilloscope enables signal capture over a long observation period of up to 1000000 segments.

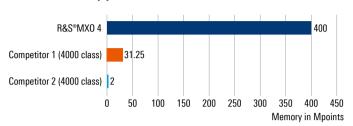
Standard history capability

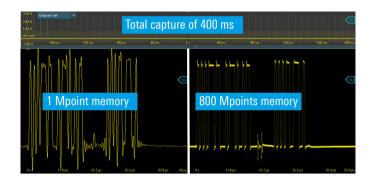
Press stop and use history mode to see previously captured acquisitions. History mode is an always-on capability. All measurement and analysis tools are available in history mode, including the serial bus decoding and automatic measurements.

Need even more memory?

During tests that involve looking at power up/power down behavior or decoding bus events over a longer period of time, there is always the wish to record longer time intervals. The memory extension option turns on 800 Mpoints (2 channels interleaved), up to 1000000 segments and up to 1000000 acquisitions.

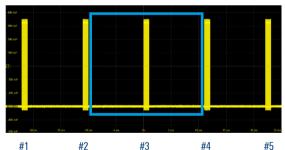
Standard memory per channel



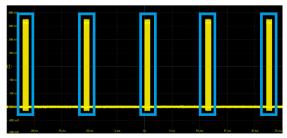


Traditional single-shot acquisition

Total acquisition time = memory depth/sample rate







Segmented memory acquisition

Acquisition time per segment = memory depth/# of segments

ISOLATE EVENTS WITH MORE PRECISION

HIGH-PRECISION DIGITAL TRIGGER

- ► Industry's most sensitive trigger: 0.0001 vertical division
- Best in class trigger jitter of just 1 ps
- ▶ World's fastest trigger rearm time of < 21 ns</p>
- Adjustable digital trigger filters
- User definable hysteresis

Modern digital trigger

The MXO-EP ASIC incorporates the Rohde & Schwarz patented digital trigger system. With digital triggering, signal measurement and triggering take place in a common path, whereas with older analog trigger architectures, incoming signals are split and fed to a measurement and a trigger path. Digital triggers offer numerous advantages.

Adjustable digital trigger filters

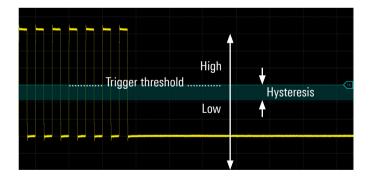
Use the up to 18-bit HD mode for triggering to reduce measurement system noise. The digital trigger architecture makes it possible to adapt the cutoff frequency of the digital lowpass filter to the signal to be measured. Unlike oscilloscopes with analog trigger circuits, the same filter settings can be used for both the trigger signal and the measurement signal. As a result, noise on the trigger signal can be suppressed, for instance while simultaneously capturing and displaying the filtered or unfiltered measurement signal.

World's most sensitive trigger

The R&S®MXO 4 series digital trigger is up to 10000 times more sensitive than the trigger systems of all competitors that are still using older analog trigger architectures. High trigger sensitivity enables users to isolate difficult-to-find small physical layer anomalies in the presence of large signals, accelerating debugging and troubleshooting.

User definable hysteresis

Use automated trigger hysteresis settings or manually enter your values. Unlike using oscilloscopes with analog triggers, R&S®MXO 4 series users have full access to control all trigger hysteresis settings. This provides additional flexibility for determining where to trigger, including how much trigger noise suppression is desired.





SPECTRUM ANALYSIS

SUPERIOR RF MEASUREMENT CAPABILITY

- ► Pristine RF spectrum
- **Dedicated RF controls**
- RF/time domain views with independent controls
- Gated spectrum for easy correlation between frequency and time

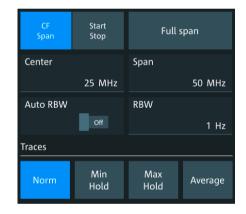
RF insights into your measurements

The R&S®MXO 4 series oscilloscope is engineered with spectrum analysis in mind to bring forward fast and powerful analysis capabilities. It boasts an industry leading spectrum acquisition rate of 45 000 FFT/s. This allows capture of spurious spectrum events, especially when doing EMI debugging. The pristine RF characteristics of the instrument deliver great spectrum performance together with a synchronized time domain view.

RF characteristics	
Spectrum update rate	> 45 000 FFT/s
Sensitivity/noise power density	–160 dBm (1 Hz)
Noise figure	14 dB
Dynamic range	106 dB
Spurious-free dynamic range (SFDR)	65 dBc
Second harmonic distortion	-60 dBc
Third harmonic distortion	-59 dBc

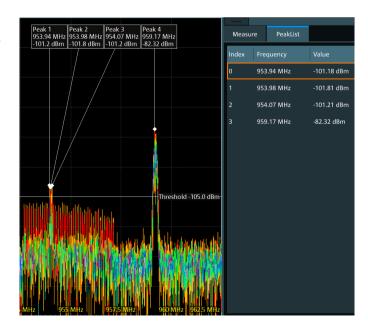
Frequency analysis setup made easy

You can configure spectrum analysis measurements on the R&S®MXO 4 by simply entering typical parameters: center frequency, span and resolution bandwidth (RBW). The spectrum settings are independent of the time domain settings but the time and frequency domains are time-correlated.



Automatic peak list and max./min. hold measurements

Rohde & Schwarz understands the need for additional tools in spectrum measurements. This is why the R&S®MXO 4 includes advanced spectrum analysis functions like max. and min. hold as well as peak list indication as part of the standard features. The values in the peak list are also shown in the diagram, allowing easy correlation and quick insights into the spectrum diagram.



SUPERIOR USER EXPERIENCE

ADVANCED USABILITY, EASY DOCUMENTATION, FAST REMOTE CONTROL

Quick access to important tools

The toolbar 1 enables quick access to important tools. Choose from a variety of tools and arrange them with maximum flexibility. The main menu 2 provides access to all instrument settings. The keys 3 left of the main menu key enable activation of the desired signals and provide quick access to analog channel, math function, FFT, arbitrary waveform generator and serial bus analysis settings.

R&S®SmartGrid

Configure your individual waveform layout on the screen using the R&S°SmartGrid function 4. See the fundamental signal parameters in the signal bar 5. From here, drag & drop waveforms into the R&S°SmartGrid and arrange them as desired. Superimposing waveforms is also possible.



Enhanced touchability

The box design 6 implemented for all instrument settings provides enhanced touchability. Tap on any part of a box to change the value of the parameter.

Search function

Easily find any oscilloscope capability you are looking for by simply typing it into the search box 7.

Save results fast

Save waveforms in various file formats or download them via Ethernet or USB for later analysis with MATLAB® or Excel. You can also save screen content, measurement data and reports.

Documentation at the press of a key

Document your measurements quickly:

- Screenshots including waveforms and results
- ► Clear grid annotations for easy-to-read signal characteristics
- ► Color-coded labeling to highlight signal portions of interest, e.g. anomalies
- ► Save waveforms and measurement results in binary or CSV format for signal analysis on a PC

Documentation				
Contents	waveform	complete		
		selection (zoom, cursor, gate, manual)		
		number of acquisitions		
		history memory		
		measurement results		
Format	measurement data	binary, CSV, 1 to 4 channels		
	graphics	PNG, JPG, BMP, TIF, PDF		
Drivers		VXI, LabVIEW, LabWindows/CVI, .NET		
Remote control		web interface, VNC, SCPI		
Languages		choose from 13		

Remote control access: anytime, anywhere

Remotely control your R&S®MXO 4 and view the display on a PC or mobile device. View the same user interface as on the instrument itself. All oscilloscope functions are also available remotely via Ethernet or USB.

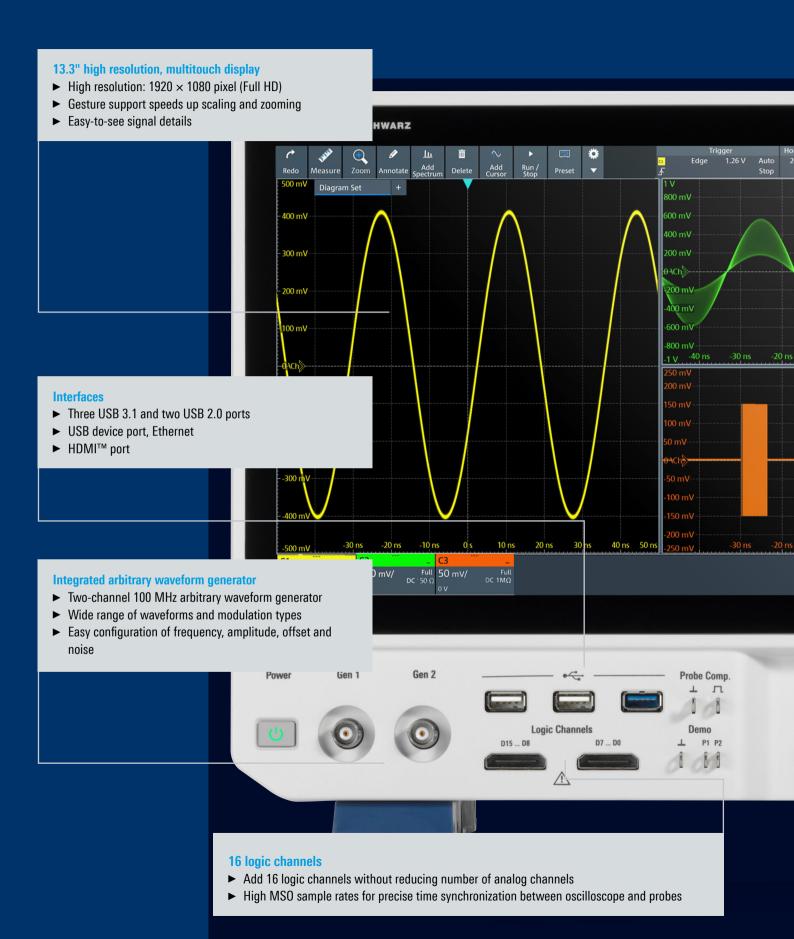


Language selection

The R&S®MXO 4 series user interface supports multiple languages. Just a few seconds are needed to switch languages while the instrument is running, making the oscilloscope truly international.



ENHANCED USABILITY



Intuitive front panel design for efficient operation

- ► Fast, direct access to primary instrument settings
- Quickly adjust settings with knobs and keys
- Sectional layout makes finding the right function easy



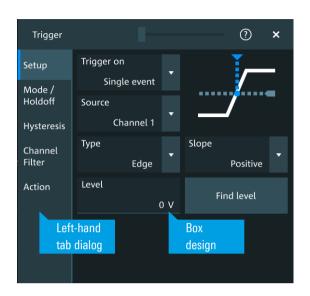
FUN TO DRIVE

15-MINUTE LEARNING CURVE, ENHANCED TOUCHABILITY, INTUITIVE NAVIGATION

Superior usability

Extensive user feedback and research into smart device user interface concepts led to the development of the R&S®MXO 4 series user interface:

- ► The main menu key in the lower right corner of the touchscreen opens a pull-up menu that provides access to all of the oscilloscope's functions. The main menu is positioned within easy reach of the front panel, so that users can quickly switch between the touchscreen and the front panel controls
- ► The left-hand tab dialogs produce small areas, maximizing the waveform viewing area
- ▶ Box design to touch anywhere in a large target area
- ► The keys in the signal bar on the lower left make it easy to turn on/off signal sources and to adjust the R&S®SmartGrid layout
- ► Unique in the industry is the toolbar for quick access to your favorite tools
- ► The toolbar can be personalized. Icons, e.g. for measurement, cursors and spectrum display, can be rearranged, added or removed
- ► Fast one-touch access to trigger setup, horizontal settings and acquisition control directly from the menu bar on the upper right
- ► Select the icon with the Rohde & Schwarz logo to see current instrument details including LAN IP and firmware version
- ► The user interface is consistent with that of the R&S®RTO6 and R&S®RTP series oscilloscopes (see photos below)









YOUR GO-TO TOOL

READY FOR MANY USES

An oscilloscope as flexible as you

Need additional test capability? Customize your R&S®MXO 4 series oscilloscope with the application software and probes that your applications need.



Need digital channels?

Add 16 digital channels with the R&S®MXO4-B1 mixed signal option (MSO). Unlike some other oscilloscopes that force a tradeoff between digital and analog channel usage, the R&S®MXO 4 series digital channels can be used simultaneously with all analog channels. Simply connect the required R&S®MXO4-B1 probes (one or two) to the R&S®MXO 4 to use the digital channels.



Need configurable waveform generation?

With the R&S®MXO4-B6 arbitrary waveform generator option, you can add two integrated 100 MHz arbitrary waveform generators. Waveforms captured on the oscilloscope can be replayed by the generator and noise can be added to create worst case performance to determine system tolerance. Select from a wide range of available waveshapes or load an arbitrary waveform.

Choose from a wide selection of compatible probes

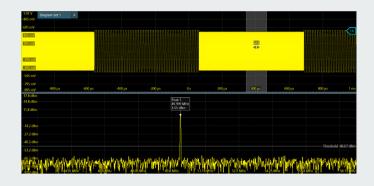
Rohde & Schwarz provides a broad portfolio of current and voltage probes. All R&S®MXO 4 series oscilloscope channel inputs include a Rohde & Schwarz probe interface connection for Rohde & Schwarz active probes. Many thirdparty probes are also compatible with the instrument.



EMI DEBUGGING

Easy navigation in frequency domain

The R&S®MXO 4 spectrum function has the familiar interface of a spectrum analyzer. The spectrum measurement setup dialog offers basic spectrum analyzer parameters such as start and stop frequency and resolution bandwidth. In spectrum mode, the R&S®MXO 4 time domain settings are unaffected. This makes navigation in the frequency domain an easy task. The maximum FFT capture bandwidth corresponds to the R&S®MXO 4 series bandwidth, allowing a quick overview of all of a DUT's emissions from 0 Hz to 1.5 GHz.



Gated spectrum for correlated time and frequency analysis

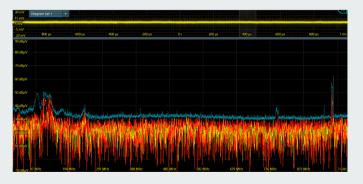
With the gated spectrum function, it is possible to restrict spectrum analysis to a user-defined region of the captured time domain signal. Excessive spectral emissions can be correlated to dedicated time periods in a signal. Typical applications include the correlation of unwanted emissions with fast switching edges in switched-mode power supplies or with data transfers on bus interfaces. Having identified the problem, the design engineer can easily check the effectiveness of remedies such as blocking capacitors or reduced rise/fall times by observing the level change of the spectral emission.

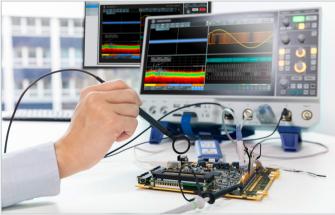
Ultra-fast spectrum acquisitions for detecting random and spurious spectrum events

The R&S®MXO 4 series architecture is optimized in terms of hardware and software to leverage the powerful MXO-EP ASIC capabilities to deliver fast and responsive spectrum captures. This is critical in detecting random and spurious emissions that are otherwise hidden due to the blind time in oscilloscope acquisitions. Spectrum analysis includes max. hold, min. hold and average functionality to keep track of spectrum events that occur during testing. These important test receiver functions come standard with the R&S®MXO 4 series spectrum function.

The right setup with the right probes

Rohde&Schwarz offers the compact R&S°HZ-15 near-field probe set, which is particularly helpful for EMI debugging of embedded designs. The most compact probe in this set allows capturing near-field emissions from single circuit lines. The R&S°HZ-15 covers the frequency range from 30 MHz to 3 GHz. With reduced sensitivity, it can also be used below 30 MHz. The optional R&S°HZ-16 preamplifier provides 20 dB gain in the frequency range from 100 kHz to 3 GHz, in case higher sensitivity is needed.





LOGIC ANALYSIS

Logic analysis enabled by default

The R&S®MXO 4 series oscilloscopes have the R&S®MXO4-B1 mixed signal option (MSO) hardware built into every instrument. The MSO option provides the logic probes required for using the 16 digital channels.

See more signal details with fast sample rate and deep memory

With a sample rate of 5 Gsample/s, the R&S®MXO 4 series oscilloscope provides high time resolution of 200 ps for all digital channels. This sample rate is available over the entire memory depth of 400 Mpoints per channel. The mixed signal option offers comprehensive trigger capabilities to detect critical events such as narrow glitches or certain logical patterns.



Analysis of low speed serial buses with digital channels

Today, high speed interfaces are often combined with low speed control or programming buses in a single device. You can use the digital channels of the R&S®MXO4-B1 option to trigger and decode low speed serial protocols such as SPI and I²C with the appropriate protocol options. All protocol analysis tools for the analog channels, such as decode table and search, are also available for the digital channels. Trigger on protocol details such as start, address and data in order to focus on dedicated events.



SERIAL BUS ANALYSIS

Dual-path protocol analysis

With the R&S®MXO 4 series, you can experience protocol analysis innovation. Traditional oscilloscopes typically capture data packets in the decoding path using the same sample rate as in the waveform path.

The R&S®MXO 4 series offers dual-path protocol analysis. You can set the instrument sample rate for the waveform path, and the oscilloscope will automatically use another internal decoupled sample rate for the decoding path. Even with very slow sample rates, the protocol data is correctly decoded. With conventional oscilloscopes, decoding would not be possible due to undersampling.



Capture more data packets with deep memory

Need to capture long time periods? You can use the R&S®MXO 4 series extended memory to capture more data packets. With a memory depth of up to 800 Mpoints, the R&S®MXO 4 can capture long periods of time where causes and effects are widely apart. During the entire capture, signal details are time-correlated with packet content for fast debugging.



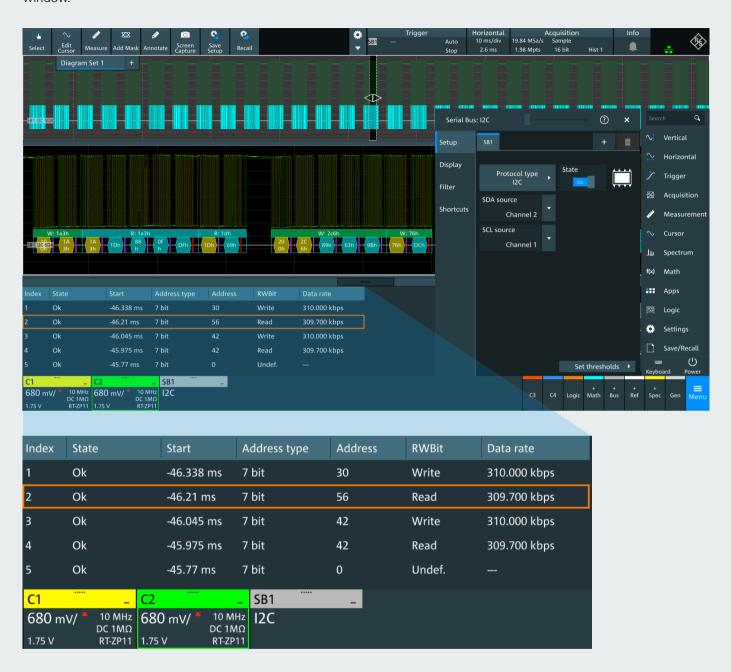
Trigger and decode packages

Option	Description	Buses
R&S®MXO4-K510	low speed serial buses	I ² C/SPI/RS-232/RS-422/RS-485/UART
R&S [®] MXO4-K520	automotive buses	CAN/CAN FD/CAN XL/LIN 1)

¹⁾ Available with future firmware release.

Individual screen setup

Zoom in and out on the decoded protocol data using the vertical and horizontal control knobs or using your fingers on the touchscreen. Use the R&S®SmartGrid function to rearrange the windows displayed on the screen to best fit your viewing preferences. The decoded bus data can be overlaid on the captured signal and/or displayed in a separate window.



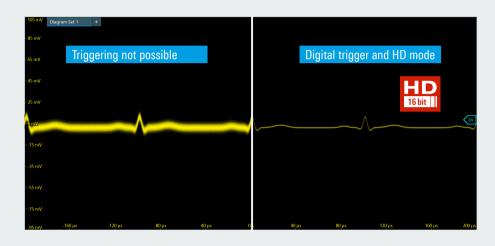
POWER ANALYSIS

See power signal details with up to 18 bit resolution

Even the smallest signal details of a highly dynamic signal matter for power measurements, for example when verifying R_{DS(on)} for a MOSFET. The HD mode of the R&S®MXO 4 series oscilloscope increases the vertical resolution up to 18 bit so that previously unseen signal details become visible and can be measured. The oscilloscope also offers adjustable digital filters that allow noise suppression resulting in sharper waveforms with more signal details.

Digital trigger for enhanced debugging capabilities

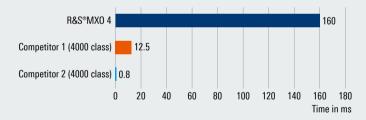
With up to 18 bit vertical resolution, the R&S®MXO 4 series digital trigger architecture enables triggering on the smallest vertical variation sampled. The R&S®MXO 4 trigger system offers sensitivity of 0.0001 div and is adjustable to factor in different trigger requirements, for example to avoid false triggering on noise. It is also possible, with the digital trigger, to adapt the filter cutoff frequency only on the trigger path while maintaining the original waveform for viewing and measurements.



Maintaining fast sample rates with deepest memory

Analyzing power up/power down and transient behavior of power supplies requires high sample rates and long recording times. With up to 800 Mpoints of memory, highest in its class, the R&S®MXO 4 series oscilloscope can record long periods of time while maintaining high sample rates of up to 5 Gsample/s.

Acquisition time (at 5 Gsample/s)



Extensive probe portfolio: high voltage and current probes

The Rohde&Schwarz portfolio of high voltage probes includes active differential probes for voltages up to 6000 V (peak). These probes offer exceptional common mode rejection over a broad frequency range. Rohde&Schwarz current probes enable accurate, non-intrusive measurements of DC and AC currents. Different models are available to measure currents in the range from 1 mA to 2000 A with a bandwidth of up to 120 MHz.



FREQUENCY RESPONSE ANALYSIS

Creating Bode plots with the R&S®MXO 4 series

Perform low frequency response analysis

The R&S®MXO4-K36 frequency response analysis (FRA) option lets you perform low frequency response analysis on your oscilloscope easily and quickly. It measures the frequency response of a variety of electronic devices, including passive filters and amplifier circuits. For switched-mode power supplies, it measures the control loop response (CLR) and power supply rejection ratio (PSRR).

The FRA option uses the oscilloscope's built-in arbitrary waveform generator to create stimulus signals in the range from 10 Hz to 100 MHz. Measuring the voltage ratios of the stimulus signal and the output signal of the DUT at each test frequency, the oscilloscope plots gain and phase logarithmically.



Features and functionalities

Amplitude profiles

The R&S®MXO4-K36 allows users to configure amplitude profiles for the generator output level. This helps optimize signal-to-noise ratio (SNR) at different frequencies when measuring CLR and PSRR. Users can also load lookup tables for generator settings.

Improved resolution and marker support

Users can define the number of points per decade to set the required resolution and sweep time. Markers can be placed on the traces with a table showing the corresponding parameter values. An auto placement function makes it easy for users to determine the phase and gain margin.

Parallel display of time domain

Parallel display of time and frequency domain allows users to monitor if an injected signal causes distortion that leads to measurement errors. These effects are hard to spot from just the Bode plot. Using the time domain window together with the Bode plot significantly facilitates adjusting the amplitude profile to the optimal level.

Result table

The measurement result table displays the frequency, gain and phase shift for each measured point. The markers and result table provide interactive display of the selected information. For reporting purposes, screenshots, result table or both can be saved to a USB device.

Broad probe portfolio

Accurate CLR and PSRR characterization is highly dependent on choosing the right probes since the peak-to-peak amplitudes of both the input and output voltages can be very low at some test frequencies. These small amplitudes could be buried in the oscilloscope's noise floor and in the switching noise of the DUT. We recommend the low-noise R&S®RT-ZP1X 38 MHz bandwidth 1:1 passive probes to reduce the attenuation error and provide the best SNR.



POWER INTEGRITY

Debugging and characterizing power rails

Accurately measure ripple and PARD

As power rail tolerance levels get smaller, it becomes increasingly difficult to measure power ripple accurately. The R&S®MXO 4 oscilloscope's low inherent noise enables accurate power integrity measurements in the millivolt range. The fast update rate of the R&S®MXO 4 series allows you to quickly see infrequent and worst-case ripple as well as periodic and random disturbances (PARD).

Power rail characterization with high fidelity probes

Wide bandwidth, high sensitivity, very low noise and extralarge DC offset make the R&S®RT-ZPR an excellent probe for characterizing power rails. With a bandwidth of up to 4 GHz, excellent sensitivity due to the 1:1 attenuation ratio and low noise, the R&S®RT-ZPR excels at precise ripple measurements. Coupled with the oscilloscope's powerful spectrum analysis capabilities, the R&S®RT-ZPR probes can be used to isolate PARD. An integrated high-precision 18-bit DC voltmeter (R&S®ProbeMeter) delivers an instantaneous DC voltage readout in parallel.



Measuring small AC voltages riding on large DC offsets

Offering ±60 V offset range, the R&S®RT-ZPR power rail probes allow you to focus on small ripples on the power rail's DC voltage. Whether you need to zoom in on a 1 V or much higher DC level, the probe provides the required offset while maintaining lowest vertical scale settings. Together with the extremely low-noise frontend of the R&S®MXO 4 oscilloscope and 18 bit vertical resolution, the large DC offset provides accelerated insight into the power integrity of your design.

Find coupled sources with fast spectrum function

With the industry's most capable spectrum function in an oscilloscope, you can analyze the behavior of switched-mode power supplies or quickly scan for sources coupled onto your power rail. The R&S®MXO 4 series oscilloscope spectrum algorithm allows you to analyze the spectrum independently of the time domain settings. This quickly provides a comprehensive picture of your power rails.



Using spectrum analysis with time gating to effectively find coupled sources that contribute to power rail noise.

INTEGRATED ARBITRARY WAVEFORM GENERATOR

Compact and configurable

Two-channel 100 MHz arbitrary waveform generator

Equipped with the R&S®MXO4-B6 option, the R&S®MXO 4 oscilloscope offers a fully integrated two-channel 100 MHz arbitrary waveform generator. With up to 625 Msample/s and 16 bit resolution, the generators are suitable for implementing prototype hardware and for educational purposes. The integrated generators provide both standard and arbitrary waveforms as stimulus signals to the DUT. They can be operated as function and/or modulation generators and also support the sweep mode.

Wide range of waveforms and modulation types

The integrated arbitrary waveform generators deliver sine, square, pulse, ramp, triangle, sinc, arbitrary and noise waveforms as stimulus signals to the DUT. For all waveforms, you can set the frequency, amplitude, offset and noise and also add bursts.

The modulation feature supports AM, FM, FSK and PWM modulations for sine, rectangle, triangle and ramp waveshapes.



Arbitrary waveform generator specifications	
Analog output	2 channels
Bandwidth	100 MHz
Amplitude	high impedance: 10 mV to 10 V (peak-to-peak), 50 Ω : 5 mV to 5 V (peak-to-peak)
Arbitrary waveform length	1 sample to 40 Msample per channel
Sample rate	1 sample/s to 312.5 Msample/s
Vertical resolution	16 bit
Operating modes	 function and arbitrary waveform generator (DC, sine, square, pulse, triangle, ramp, inverse ramp, sinc, arbitrary) modulation (AM, FM, FSK, PWM) frequency sweep noise

EXTENSIVE PROBE PORTFOLIO

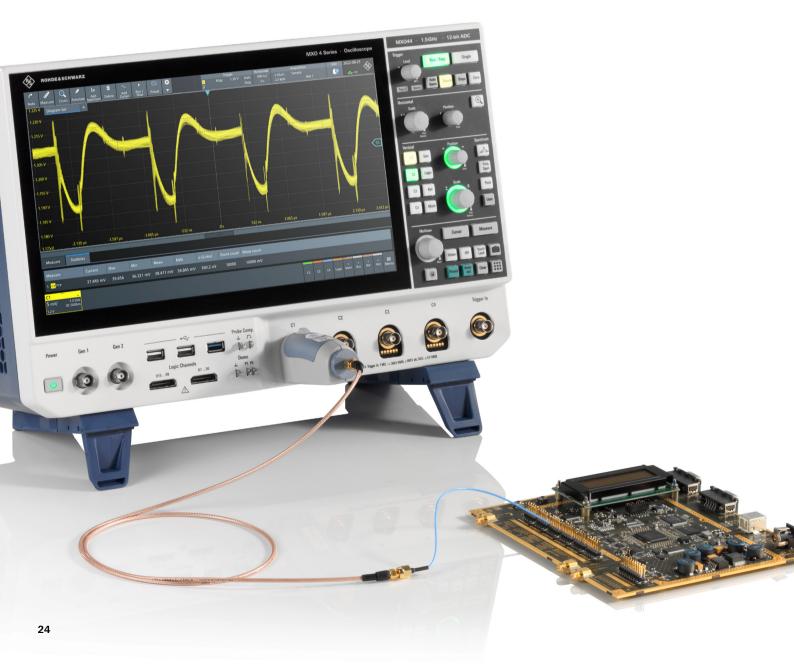
THE RIGHT PROBE FOR THE BEST MEASUREMENT

Extensive range of probes for all measurement tasks

A complete portfolio of high-quality passive and active probes covers all measurement tasks. With an input impedance of 1 M Ω , the active probes only put a minimum load on the signal source operating point. The active single-ended probes offer a very wide dynamic range, e.g. 60 V (V $_{pp}$) at 1 GHz, even at high frequencies, preventing signal distortion.

Complete portfolio for power measurements

The portfolio of dedicated power measurement probes includes active and passive probes for different voltage and current ranges – from μA to kA and from μV to kV. Dedicated power rail probes help detect even small and sporadic distortions on DC power rails.



Micro button for convenient instrument control

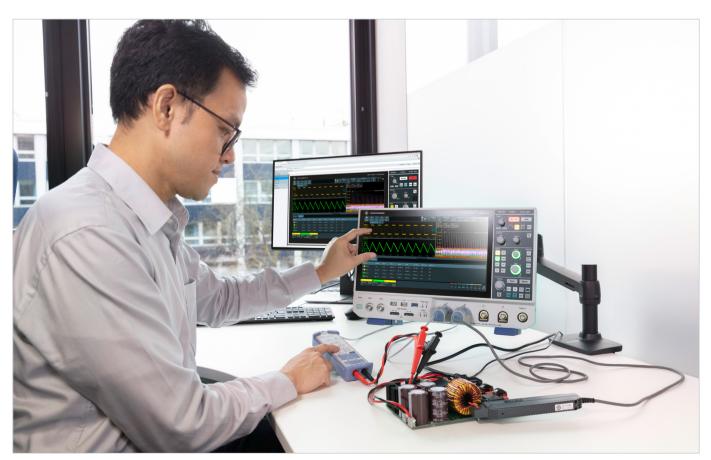
The situation is familiar to every engineer: You have carefully positioned the probe on the DUT and you want to start measuring, but you do not have a free hand. The micro button on Rohde & Schwarz active probes solves the problem. It is conveniently located close to the probe tip, and you can assign it different functions such as run/stop, autoset and adjust offset.

Micro button

High voltage differential probes

The R&S®RT-ZHD series high voltage differential probes provide an excellent common mode rejection ratio (CMRR) over a wide bandwidth of up to 200 MHz and can safely measure up to 6000 V peak voltages. These probes exhibit exceptionally low noise, making them ideal for switching power analysis.

Like all active probes from Rohde & Schwarz, the R&S®RT-ZHD probes are equipped with the R&S®ProbeMeter, a high-precision DC voltmeter offering 0.1% accuracy while ensuring 0.5% gain accuracy and very low measurement drift. They also have an integrated 5 MHz analog filter, an audible common mode voltage overrange indicator and a micro button to give users full awareness of and control over the probe measurements.



High voltage differential probes for switching power analysis measurements.

Rohde & Schwarz has a comprehensive probe portfolio to meet every probing need.

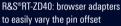
For more information, see product brochure
 "Probes and accessories for Rohde & Schwarz oscilloscopes" (PD 3606.8866.12)













R&S®RT-ZA15 external attenuator for R&S®RT-ZD20/-ZD30







Passive probes included as standard (38 MHz to 700 MHz)

R&S°RT-ZP11, R&S°RT-ZP1X

Passive broadband probes (8 GHz)

R&S®RT-ZZ80

Active single-ended broadband probes (1 GHz to 6 GHz)

R&S°RT-ZS10L, R&S°RT-ZS10E, R&S°RT-ZS10, R&S°RT-ZS20, R&S°RT-ZS30, R&S°RT-ZS60

Active differential broadband probes (1 GHz to 4.5 GHz)

R&S°RT-ZD10, R&S°RT-ZD20, R&S°RT-ZD30, R&S°RT-ZD40

(I GHZ to 4.5 GHZ)

Rohde & Schwarz oscilloscope. They are low cost, general purpose probing solutions for a broad range of applications.

Passive probes come standard with every

These are an economical yet powerful alternative to active probes for measuring high speed signals on low impedance lines. Their input impedance is low and remains practically constant over the entire bandwidth. They feature extremely low input capacitance, very low noise and high linearity.

A very high dynamic range and exceptionally low offset and gain errors combined with the right accessories make these probes ideal for use with Rohde & Schwarz oscilloscopes.

A flat frequency response and high input impedance with low input capacitance permit precise measurements on differential signals while keeping the load on the DUT low. The high common mode rejection over the entire probe bandwidth ensures high immunity to interference. Special browser adapters allow flexible contacting with high signal fidelity.

Power rail probes (2 GHz and 4 GHz)

R&S®RT-ZPR20, R&S®RT-ZPR40

High voltage probes (100 MHz to 400 MHz; ±750 V to ±6000 V)

R&S°RT-ZH03, R&S°RT-ZH10, R&S°RT-ZH11, R&S°RT-ZD01, R&S°RT-ZHD07, R&S°RT-ZHD15, R&S°RT-ZHD16, R&S°RT-ZHD60

Current probes (20 kHz to 120 MHz; ±1 mA to ±2000 A)

R&S°RT-ZC02, R&S°RT-ZC03, R&S°RT-ZC05B, R&S°RT-ZC10, R&S°RT-ZC15B, R&S°RT-ZC15B, R&S°RT-ZC20, R&S°RT-ZC30, R&S°RT-ZC31

EMC near-field probes (30 MHz to 3 GHz)

R&S°HZ-15, R&S°HZ-17

Wide bandwidth, high sensitivity, very low noise and extra-large DC offset make these probes an excellent tool for characterizing power rails. The integrated high-precision DC voltmeter (R&S°ProbeMeter) provides instantaneous DC voltage readout.

The Rohde&Schwarz portfolio of high voltage probes includes passive single-ended and active differential probes for voltages up to 6000 V (peak). Different models allow measurements in up to CAT IV environments. Differential probes provide exceptional common mode rejection over a wide bandwidth.

Rohde & Schwarz current probes enable accurate, non-intrusive measurements of DC and AC currents. Different models are available to measure currents in the range from 1 mA to 2000 A with a bandwidth of up to 120 MHz. Current probes are available with the Rohde & Schwarz probe interface or a BNC connector for an external power supply.

Powerful E and H near-field probes for the frequency range from 30 MHz to 3 GHz with an optional preamplifier expand the application range of the R&S°MXO 4 series oscilloscope to include EMI debugging.

AND THERE IS SO MUCH MORE ...

AN OSCILLOSCOPE THAT EVOLVES WITH YOUR NEEDS

Grows with your needs – fully software based upgrades

The R&S®MXO 4 series flexibly adapts to evolving requirements for your project. The R&S®MXO 4 oscilloscopes come equipped with all hardware and software options. To enable a desired option, all you have to do is purchase a software license and activate the function or upgrade via keycode. This includes bandwidth upgrades up to 1.5 GHz, mixed signal option, memory upgrade, arbitrary waveform generator, serial bus triggering and decoding, and frequency response analysis. This makes retrofitting very easy.

Regular firmware improvements

Regular firmware updates consistently add new functions to the R&S®MXO 4 series oscilloscopes. Download the latest firmware version at www.rohde-schwarz.com and use a USB storage device or LAN connection for installation. This will keep your R&S®MXO 4 series oscilloscope up to date.

Multilingual support: choose among thirteen languages

The user interface and online help of the R&S®MXO 4 series oscilloscopes support thirteen languages (English, German, French, Spanish, Italian, Portuguese, Czech, Polish, Russian, Simplified and Traditional Chinese, Korean and Japanese). You can change the language in just a few seconds while the instrument is running.

Safe transport and easy rack mounting

An extensive selection of storage and transportation accessories means the R&S®MXO 4 series oscilloscopes are always fully protected and easy to transport. The rackmount kit allows easy installation of the oscilloscope in integrated environments.



R&S®MXO4-Z1
R&S®MXO4-Z3
R&S®MXO4-Z4
R&S°ZZA-MXO4
100 mm × 100 mm VESA standard pattern on the rear of all instruments





OSCILLOSCOPE PORTFOLIO











		- W		n - im 6 16 5 5 5 6	and the same of th
	R&S®RTH1000	R&S®RTC1000	R&S®RTB2000	R&S®RTM3000	R&S®MXO 4
Vertical system					
Bandwidth 1)	60/100/200/350/500 MHz	50/70/100/200/300 MHz	70/100/200/300 MHz	100/200/350/500 MHz/1 GHz	200/350/500 MHz/1/1.5 GHz
Number of channels	2 plus DMM/4	2	2/4	2/4	4
ADC resolution; system architecture	10 bit; 16 bit	8 bit; 16 bit	10 bit; 16 bit	10 bit; 16 bit	12 bit; 18 bit
V/div, 1 MΩ	2 mV to 100 V	1 mV to 10 V	1 mV to 5 V	500 μV to 10 V	$500~\mu V$ to $10~V$
V/div, 50 Ω	-			500 μV to 1 V	500 μV to 1 V
Horizontal system					
Sampling rate per channel (in Gsample/s)	1.25 (4-channel model); 2.5 (2-channel model); 5 (all channels interleaved)	1; 2 (2 channels interleaved)	1.25; 2.5 (2 channels interleaved)	2.5; 5 (2 channels interleaved)	2.5; 5 (2 channels interleaved)
Maximum memory (per channel; 1 channel active)	125 kpoints (4-channel model); 250 kpoints (2-channel model); 500 kpoints	1 Mpoints; 2 Mpoints	10 Mpoints; 20 Mpoints	40 Mpoints; 80 Mpoints	standard: 400 Mpoints; max. upgrade: 800 Mpoints ²⁾
Segmented memory	standard, 50 Mpoints	_	option, 320 Mpoints	option, 400 Mpoints	standard: 10 000 segments; option: 1 000 000 segments
Acquisition rate (in waveforms/s)	50 000	10 000	50 000 (300 000 in fast segmented memory mode ²⁾)	64 000 (2 000 000 in fast segmented memory mode ²⁾)	> 4500000
Trigger					
Types	digital	analog	analog	analog	digital
Sensitivity	-	-	at 1 mV/div: > 2 div	at 1 mV/div: > 2 div	0.0001 div, across full bandwidth, user controllable
Mixed signal option (MSO)					
Number of digital channels 1)	8	8	16	16	16
Analysis					
Mask test	tolerance mask	tolerance mask	tolerance mask	tolerance mask	3)
Mathematics	elementary	elementary	basic (math on math)	basic (math on math)	basic (math on math)
Serial protocols triggering and decoding ¹⁾	I ² C, SPI, UART/RS-232/ RS-422/RS-485, CAN, LIN, CAN FD, SENT	l ² C, SPI, UART/RS-232/ RS-422/RS-485, CAN, LIN	I ² C, SPI, UART/RS-232/ RS-422/RS-485, CAN, LIN	I ² C, SPI, UART/RS-232/RS-422/ RS-485, CAN, LIN, I ² S, MIL-STD-1553, ARINC 429	I ² C, SPI, UART/RS-232/RS-422/ RS-485, CAN, CAN FD, CAN XL, LIN ³⁾
Applications 11, 2)	high-resolution frequency counter, advanced spectrum analysis, harmonics analysis, user scripting	digital voltmeter (DVM), component tester, fast Fourier transform (FFT)	digital voltmeter (DVM), fast Fourier transform (FFT), frequency response analysis	power, digital voltmeter (DVM), spectrum analysis and spectro- gram, frequency response analysis	frequency response analysis
Compliance testing 1), 2)	-	-	-	-	-
Display and operation					
Size and resolution	7" touchscreen, 800 × 480 pixel	6.5", 640 × 480 pixel	10.1" touchscreen, 1280 × 800 pixel	10.1" touchscreen, 1280 × 800 pixel	13.3" touchscreen, 1920 × 1080 pixel (Full HD)
General data					
Dimensions in mm	201 × 293 × 74	285 × 175 × 140	390 × 220 × 152	390 × 220 × 152	414 × 279 × 162
$(W \times H \times D)$					
(W x H x D) Weight in kg	2.4	1.7	2.5	3.3	6

¹⁾ Upgradeable.

²⁾ Requires an option.

³⁾ Available with future firmware release.







R&S®RTE1000	R&S®RTO6	R&S®RTP
200/350/500 MHz/1/1.5/2 GHz 2/4	600 MHz/1/2/3/4/6 GHz 4	4/6/8/13/16 GHz 4
8 bit; 16 bit	8 bit; 16 bit	8 bit; 16 bit
500 μV to 10 V	1 mV to 10 V (HD mode: 500 μV to 10 V)	
500 μV to 1 V	1 mV to 1 V (HD mode: 500 µV to 1 V)	2 mV to 1 V (HD mode: 1 mV to 1 V)
5	10; 20 (2 channels interleaved in 4 GHz and 6 GHz model)	20; 40 (2 channels interleaved)
50 Mpoints; 200 Mpoints	standard: 200 Mpoints/800 Mpoints; max. upgrade: 1 Gpoints/2 Gpoints	standard: 100 Mpoints/400 Mpoints; max. upgrade: 3 Gpoints
standard	standard	standard
1 000 000 (1 600 000 in ultra-segmented memory mode)	1000000 (2500000 in ultra-segmented memory mode)	750000 (3200000 in ultra-segmented memory mode)
digital	digital (includes zone trigger)	advanced (includes zone trigger), digital trigger (14 trigger types) with real-time deembedding ²⁾ , high speed serial pattern trigger including 8/16 Gbps clock data recovery (CDR) ²⁾
0.0001 div, across full bandwidth, user controllable	0.0001 div, across full bandwidth, user controllable	0.0001 div, across full bandwidth, user controllable
16	16	16
user configurable, hardware based	user configurable, hardware based	user configurable, hardware based
advanced (formula editor)	advanced (formula editor, Python interface)	advanced (formula editor, Python interface)
I ² C, SPI, UART/RS-232/RS-422/RS-485, CAN, LIN, I ² S, MIL-STD-1553, ARINC 429, FlexRay™, CAN FD, USB 2.0/HSIC, Ethernet, Manchester, NRZ, SENT, SpaceWire, CXPI, USB Power Delivery, Automotive Ethernet 100BASE-T1	I ² C, SPI, UART/RS-232/RS-422/RS-485, CAN, LIN, I ² S, MIL-STD-1553, ARINC 429, FlexRay™, CAN FD, MIPI RFFE, USB 2.0/HSIC, MDIO, 8b10b, Ethernet, Manchester, NRZ, SENT, MIPI D-PHY, SpaceWire, MIPI M-PHY/UniPro, CXPI, USB 3.1 Gen 1, USB-SSIC, PCIe 1.1/2.0, USB Power Delivery, Automotive Ethernet 100/1000BASE-T1	I°C, SPI, UART/RS-232/RS-422/RS-485, SENT, CAN, LIN, CAN FD, MIL-STD-1553, ARINC 429, SpaceWire, USB 2.0/HSIC/PD, USB 3.1 Gen 1/Gen 2/SSIC, PCle 1.1/2.0/3.0, 8b10b, MIPI RFFE, MIPI D/M-PHY/ UniPro, Automotive Ethernet 100/1000BASE-T1, Ethernet 10/100BASE-TX, MDIO, Manchester, NRZ
power, advanced spectrum analysis and spectrogram	power, advanced spectrum analysis and spectrogram, jitter and noise decomposition, clock data recovery (CDR), I/Q data and RF analysis (R&S®VSE), deembedding, TDR/TDT analysis	advanced spectrum analysis and spectrogram, jitter and noise decomposition, real-time deembedding, TDR/TDT analysis, I/Q data and RF analysis (R&S°VSE), advanced eye diagram
-	see data sheet (PD 5216.1640.22)	see data sheet (PD 3683.5616.22)
10.4%	15.0" *****	12.0" *****
10.4" touchscreen, 1024 × 768 pixel	15.6" touchscreen, 1920 x 1080 pixel (Full HD)	13.3" touchscreen, 1920 × 1080 pixel (Full HD)
427 × 249 × 204	450 × 315 × 204	441 × 285 × 316
8.6	10.7	18
-	-	-

SPECIFICATIONS OF BASE UNIT

Input channels		4 channels
Input impedance		50 Ω ± 1.5%, 1 M Ω ± 1% 12 pF (meas.)
Analog bandwidth (–3 dB)	at 50 Ω input impedance	
	R&S®MXO 4	≥ 200 MHz
	R&S®MXO 4 with R&S®MXO4-B243 option	≥ 350 MHz
	R&S®MXO 4 with R&S®MXO4-B245 option	≥ 500 MHz
	R&S®MXO 4 with R&S®MXO4-B2410 option	≥ 1 GHz
	R&S®MXO 4 with R&S®MXO4-B2415 option	≥ 1.5 GHz ¹⁾
	at 1 M Ω input impedance	2 110 0112
	R&S®MXO 4	≥ 200 MHz (meas.)
	R&S®MXO 4 with R&S®MXO4-B243 option	≥ 350 MHz (meas.)
	R&S®MXO 4 with R&S®MXO4-B245 option	≥ 500 MHz (meas.)
	R&S®MXO 4 with R&S®MXO4-B2410 option	≥ 700 MHz (meas.) ²⁾
	R&S®MXO 4 with R&S®MXO4-B2415 option	≥ 700 MHz (meas.) ²⁾
Bandwidth limits	max. –1.5 dB, min. –4 dB	1 GHz, 500/350/200/100/50/20 MHz (meas.)
Rise/fall time (calculated)	10% to 90% at $50~\Omega$	
	R&S®MXO 4	< 1.75 ns
	R&S®MXO 4 with R&S®MXO4-B243 option	< 1 ns
	R&S®MXO 4 with R&S®MXO4-B245 option	< 700 ps
	R&S®MXO 4 with R&S®MXO4-B2410 option	< 350 ps
	R&S®MXO 4 with R&S®MXO4-B2415 option	< 234 ps
	That With That With B2410 option	12 bit,
Vertical resolution		up to 18 bit for high-definition (HD) mode
		0.5 mV/div to 1 V/div,
Input sensitivity	at 50 Ω	entire analog bandwidth supported for all input sensitivities
	at 1 MΩ	0.5 mV/div to 10 V/div, entire analog bandwidth supported for all input sensitivities
DC gain accuracy	offset and position set to 0 V, after self-alignment	
9	input sensitivity > 5 mV/div	±1% of full scale
	input sensitivity ≤ 5 mV/div to ≥ 1 mV/div	±1.5% of full scale
	input sensitivity < 1 mV/div	±2.5% of full scale
lead to a collect		
Input coupling	at 50 Ω	DC
	at 1 MΩ	DC, AC
Maximum input voltage	at 50 Ω	5 V (RMS), 30 V (V _p)
	at 1 MΩ	300 V (RMS), 400 V (V $_{\rm p}$), derates at 20 dB/deca to 5 V (RMS) above 250 kHz
	at 1 MΩ with R&S°RT-ZP11 passive probe	400 V (RMS), 1650 V (V _p), 300 V (RMS) (CAT II);
		for derating and details, see R&S®RT-Zxx Standard Probes data sheet (PD 3607.3851.22)
Position range		
-	input sensitivity	Standard Probes data sheet (PD 3607.3851.22)
-	input sensitivity 100 mV/div to 1 V/div	Standard Probes data sheet (PD 3607.3851.22) ±5 div
-	100 mV/div to 1 V/div	Standard Probes data sheet (PD 3607.3851.22) ±5 div
Offset range at 50 Ω	100 mV/div to 1 V/div 0.5 mV/div to < 100 mV/div	Standard Probes data sheet (PD 3607.3851.22) ±5 div
Offset range at 50 Ω	100 mV/div to 1 V/div 0.5 mV/div to < 100 mV/div input sensitivity	Standard Probes data sheet (PD 3607.3851.22) ±5 div ±20 V ±5 V
Offset range at 50 Ω	100 mV/div to 1 V/div 0.5 mV/div to < 100 mV/div input sensitivity 800 mV/div to 10 V/div	Standard Probes data sheet (PD 3607.3851.22) ±5 div ±20 V ±200 V
Offset range at 50 Ω	100 mV/div to 1 V/div 0.5 mV/div to < 100 mV/div input sensitivity 800 mV/div to 10 V/div 80 mV/div to < 800 mV/div	Standard Probes data sheet (PD 3607.3851.22) ±5 div ±20 V ±200 V ±50 V
Offset range at 50 Ω	100 mV/div to 1 V/div 0.5 mV/div to < 100 mV/div input sensitivity 800 mV/div to 10 V/div	Standard Probes data sheet (PD 3607.3851.22) ±5 div ±20 V ±5 V ±200 V ±50 V ±(5 V – input sensitivity × position)
Position range Offset range at 50 Ω Offset range at 1 MΩ Offset accuracy	100 mV/div to 1 V/div 0.5 mV/div to < 100 mV/div input sensitivity 800 mV/div to 10 V/div 80 mV/div to < 800 mV/div	Standard Probes data sheet (PD 3607.3851.22) ±5 div ±20 V ±200 V ±50 V
Offset range at 50 Ω	100 mV/div to 1 V/div 0.5 mV/div to < 100 mV/div input sensitivity 800 mV/div to 10 V/div 80 mV/div to < 800 mV/div	Standard Probes data sheet (PD 3607.3851.22) ±5 div ±20 V ±5 V ±200 V ±50 V ±(5 V – input sensitivity × position) ±(0.35 % × net offset + 0.5 mV + 0.1 div × input sensitivity

 $^{^{1)}}$ 1.5 GHz analog bandwidth in interleave mode with 5 Gsample/s real-time sampling rate.

²⁾ With R&S®RT-ZP11 passive probe.

MS noise floor 3)						
At 50 Ω (meas.)	Input sensitivity	Analog bandwi	dth (–3 dB)			
		20 MHz	200 MHz	350 MHz	500 MHz	1 GHz
	0.5 mV/div	20 μV	43 μV	47 μV	50 μV	98 μV
	1 mV/div	22 μV	45 μV	50 μV	54 μV	104 μV
	2 mV/div	25 μV	52 μV	56 μV	61 µV	116 μV
	5 mV/div	43 μV	72 µV	77 μV	84 μV	152 μV
	10 mV/div	76 μV	118 μV	120 μV	131 μV	238 μV
	20 mV/div	148 μV	219 μV	219 μV	241 μV	436 μV
	50 mV/div	360 μV	508 μV	492 μV	543 μV	1.01 mV
	100 mV/div	747 μV	1.17 mV	1.19 mV	1.30 mV	2.47 mV
	200 mV/div	1.40 mV	2.13 mV	2.14 mV	2.34 mV	4.43 mV
	500 mV/div	3.47 mV	4.91 mV	4.80 mV	5.27 mV	10.13 mV
	1 V/div	6.88 mV	9.71 mV	9.47 mV	10.41 mV	19.96 mV
At 1 MΩ (meas.)	Input sensitivity	Analog bandwidth (–3 dB)				
		20 MHz	100 MHz	200 MHz	350 MHz	500 MHz
	0.5 mV/div	28 μV	40 μV	42 µV	47 μV	51 μV
	1 mV/div	28 μV	40 μV	46 μV	50 μV	53 μV
	2 mV/div	30 μV	43 μV	49 μV	54 μV	58 μV
	5 mV/div	44 µV	58 μV	67 μV	71 µV	78 μV
	10 mV/div	73 μV	92 μV	109 μV	109 μV	120 μV
	20 mV/div	138 μV	169 μV	199 μV	198 μV	218 μV
	50 mV/div	344 μV	442 µV	525 μV	529 μV	586 μV
	100 mV/div	739 μV	959 μV	1.13 mV	1.14 mV	1.24 mV
	200 mV/div	1.40 mV	1.74 mV	2.06 mV	2.07 mV	2.27 mV
	500 mV/div	3.47 mV	4.43 mV	5.22 mV	5.28 mV	5.75 mV
	1 V/div	7.11 mV	8.92 mV	10.44 mV	10.53 mV	11.49 mV
	2 V/div	13.83 mV	16.9 mV	19.87 mV	19.56 mV	21.38 mV
	Z V/GIV					
	5 V/div	34.84 mV	44.32 mV	52.43 mV	53.39 mV	57.97 mV
		34.84 mV 57.16 mV	44.32 mV 68.58 mV	52.43 mV 80.66 mV	53.39 mV 78.53 mV	57.97 mV 85.46 mV

Vertical system: digital channels		
Input channels		16 logic channels (D0 to D15)
Arrangement of input channels		arranged in two logic probes with 8 channels each; assignment of logic probes to channels (D0 to D7 and D8 to D15) displayed on probes
Input impedance		100 k Ω ± 2% ~4 pF (meas.) at probe tips
Maximum input frequency	signal with minimum input voltage swing and hysteresis setting "normal"	400 MHz (meas.)
Maximum input voltage		±40 V (V _p)
Minimum input voltage swing		500 mV (V _{pp}) (meas.)
Threshold groups		D0 to D3, D4 to D7, D8 to D11 and D12 to D15
Threshold level	range	±8 V in 25 mV steps
	predefined	CMOS 5.0 V, CMOS 3.3 V, CMOS 2.5 V, TTL, ECL, PECL, LVPECL
Threshold accuracy	threshold level between ±4 V	±(100 mV + 3% of threshold setting)
Comparator hysteresis		normal, robust, maximum

 $^{^{3)}~}$ HD mode active for bandwidths $\leq 500~MHz.$

Horizontal system		
Timebase range		selectable between 200 ps/div and 10 000 s/div, time per div settable to any value within range
Channel-to-channel deskew range	between analog channels	±100 ns
	between digital channels	±100 ns
Reference position		0% to 100% of measurement display area
Horizontal position range (trigger offset range)	max.	+(memory depth/current sampling rate)
	min.	-5000 s
Modes		normal
Channel-to-channel skew	between analog channels	< 100 ps (meas.)
	between digital channels	< 500 ps (meas.)
Timebase accuracy	after delivery/calibration, at +23°C	±0.2 ppm
	during calibration interval	±1 ppm
Delta time accuracy	corresponds to time error between two edges of equal polarity on same acquisition and channel; signal amplitude greater than 5 div, measurement threshold set to 50%, vertical gain 10 mV/div or greater; rise time lower than four sampling periods; waveform acquired in real-time mode	±(0.20/real-time sampling rate + timebase accuracy × reading) (peak) (meas.)

Acquisition system		
Sampling rate	analog channels (real time)	max. 5 Gsample/s on 2 channels, max. 2.5 Gsample/s on 4 channels
	analog channels (interpolated)	max. 5 Tsample/s
	digital channels	max. 5 Gsample/s on each channel
Waveform acquisition rate	max.	> 4500000 waveforms/s
Trigger rearm time	min.	< 21 ns
Memory depth ⁴⁾	standard	400 Mpoints with 4 active channels (single-shot), 400 Mpoints with 2 active channels (continuous)
	with R&S®MXO4-B108 option	800 Mpoints with 2 active channels (single-shot), 800 Mpoints with 1 active channel (continuous)
Acquisition modes	sample	middle sample in decimation interval
	peak detect	largest and smallest sample in decimation interval
	average	average value of samples in decimation interval
	number of averaged waveforms	2 to 16777215
	envelope	envelope of acquired waveforms
Sampling modes	real-time	max. sampling rate depending on ADC
	interpolated time	enhancement of sampling resolution by interpolation; max. equivalent sampling rate is 5 Tsample/s
Interpolation modes		linear, sin(x)/x, sample&hold
Fast segmentation mode	continuous recording of waveforms in acquisition memory without interruption due to visualiza	
	max. real-time waveform acquisition rate	> 4600000 waveforms/s
	min. blind time between consecutive acquisitions	< 21 ns

High-definition (HD) mode			
General description	leading to reduced noise. Because of	The high-definition mode increases the bit resolution of waveform signals by using digital filtering, leading to reduced noise. Because of the R&S®MXO 4 series digital trigger concept, signals with higher bit resolution are used as inputs to the trigger.	
Bit resolution	bandwidth, at 5 Gsample/s	bit resolution	
	1 kHz to 10 MHz	18 bit	
	100 MHz	16 bit	
	200 MHz	15 bit	
	500 MHz	14 bit	
Real-time sampling rate	all models	max. 5 Gsample/s on 2 channels, max. 2.5 Gsample/s on 4 channels	

⁴⁾ The maximum available memory depth depends on the bit resolution of the acquired data and, therefore, on the acquisition system settings such as decimation mode, use of waveform arithmetics and high-definition (HD) mode.

Trigger system		
		analog channels (C1 to C4),
Trigger sources		digital channels (D0 to D15), trigger input, serial bus
Trigger level range		±5 div from center of screen
Trigger modes		auto, normal, single, n single
Trigger sensitivity		10 ⁻⁴ div, from DC to instrument bandwidth for all vertical scales
Trigger jitter	full-scale sine wave of frequency set to –3 dB bandwidth	< 1 ps (RMS) (meas.)
Coupling mode	standard	same as selected channel
	HF reject	cutoff frequency selectable from 1 kHz to 500 MHz
	LF reject	attenuates frequencies < 50 kHz
Trigger hysteresis	modes	auto (default setting) or manual
	sensitivity	10 ⁻⁴ div, from DC to instrument bandwidth for all vertical scales
Holdoff range	time	100 ns to 10 s, fixed and random
Main trigger modes	tion and the second sec	Mark Arrad In al
Edge	triggers on specified edge (positive, negative or either	
Glitch	triggers on glitches of positive, negative or either width	
	glitch width	200 ps to 1000 s
Width	triggers on positive or negative pulse of specified outside a specified range	width; width can be shorter, longer, inside or
	pulse width	200 ps to 1000 s
Runt	triggers on pulse of positive, negative or either polarity that crosses one threshold but fails to cross a second threshold before crossing the first one again; runt pulse width can be arbitrary, shorter, longer, inside or outside a specified range	
	runt pulse width	200 ps to 1000 s
Window	triggers when signal enters or exits a specified voltage range; triggers also when signal stays inside or outside the voltage range for a specified period of time	
Timeout	triggers when signal stays high, low or unchanged for a specified period of time	
	timeout 0 ps to 1000 s	
Interval	triggers when the time between two consecutive shorter, longer, inside or outside a specified range	edges of the same polarity (positive or negative) is
	interval time	200 ps to 1000 s
Slew rate	triggers when the time required by a signal edge to toggle between user-defined upper and lower voltage levels is shorter, longer, inside or outside a specified range; edge slope may be positive, negative or either	
	toggle time	0 ps to 1000 s
Setup&hold	triggers on setup time and hold time violations between clock and data present on any two input channels; monitored time interval may be specified by the user in the range from –100 s to +100 s around a clock edge and must be at least 200 ps wide	
Pattern	triggers when a logical combination (AND, NAND period of time shorter, longer, inside or outside as	
State	triggers when a logical combination (AND, NAND edge (positive, negative or either) in one selected	
Advanced trigger modes		
Sequence trigger (A/B/R trigger)	triggers on B event after occurrence of A event; d interval; an optional R event resets the trigger seq	· ·
	A event	edge, glitch, width, runt, window, timeout, interval, slew rate
	B event	edge, glitch, width, runt, window, timeout, interval, slew rate
	R event	edge, glitch, width, runt, window, timeout, interval, slew rate
Serial bus trigger	optional	see dedicated triggering and decoding options in Ordering information in this product brochure
Trigger input	input impedance	50 Ω (meas.) or 1 M Ω (meas.) 11 pF (meas.)
	max. input voltage at 50 Ω	30 V (V _p)
	max. input voltage at 1 $M\Omega$	300 V (RMS), 400 V (V_p), derates at 20 dB/decade to 5 V (RMS) above 250 kHz
	trigger level	±5 V

Trigger system		
	sensitivity	
	input frequency ≤ 500 MHz	300 mV (peak-to-peak) (meas.)
	input coupling	AC, DC (50 Ω and 1 M Ω)
	trigger filters	HF reject (attenuates frequencies > 50 kHz, LF reject (attenuates frequencies < 50 kHz), noise reject
	trigger modes	edge (positive, negative or either)
Trigger output	functionality	A pulse is generated for each event triggering signal acquisition.
	output voltage	0 V to 5 V (nom.) at high impedance, 0 V to 2.5 V (nom.) at 50 Ω
	pulse width	selectable between 16 ns and 50 ms
	pulse polarity	low active or high active
	output delay	depends on trigger settings

Spectrum analysis		
General description	Spectrum analysis allows signal analysis in the frequency domain.	
Spectrum	sources channel 1, channel 2, channel 3, channel 4	
	setting parameters	center frequency, frequency span, resolution bandwidth (automatic or manual), gate position, gate width, vertical scaling, vertical position
	scaling	dBm, dBV, dBμV, V (RMS)
	span	1 Hz to 1.8 GHz ⁵⁾
	resolution bandwidth (RBW)	span/4 ≥ RBW ≥ span/6000
	windows	flat top, Hanning, Hamming, Blackman, rectangular, Kaiser Bessel, Gaussian
	trace types	normal, max. hold, min. hold, average
	max. real-time waveform acquisition rate	> 40 000 waveforms/s
Gate	delimits the display region used for spectrum analysis	
Peak list	The values in the peak list are also shown in the diagram to allow easy correlation.	

RF characteristics		
Sensitivity/noise density	at 1 GHz (measurement of power spectral density at 1 GHz at input sensitivity 2 mV/div, corresponding to –30 dBm input range of the oscilloscope, using spectrum analysis with center frequency 1 GHz, span 500 kHz, RBW 3 kHz)	–160 dBm (1 Hz) (meas.)
Noise figure	at 1 GHz (calculated based on the noise power density above)	14 dB (meas.)
Dynamic range	measured for a 1 GHz input carrier with level –3 dBm at input of oscilloscope, using spectrum analysis with center frequency 1 GHz, span 2 MHz, RBW 400 Hz at +20 MHz from center frequency	106 dB (meas.)
Absolute amplitude accuracy	0 Hz to 1.2 GHz	±1 dB (meas.)
Spurious-free dynamic range (excluding harmonics)	measured for a 250 MHz input carrier with level –3 dBm at input sensitivity 50 mV/div, using spectrum analysis with center frequency 900 MHz, span 1.8 GHz, RBW 300 kHz	65 dBc (meas.)
Second harmonic distortion	measured for a 250 MHz input carrier with level –3 dBm at input sensitivity 50 mV/div, using spectrum analysis with center frequency 900 MHz, span 1.8 GHz, RBW 300 kHz	-60 dBc (meas.)
Third harmonic distortion	measured for a 250 MHz input carrier with level –3 dBm at input sensitivity 50 mV/div, using spectrum analysis with center frequency 900 MHz, span 1.8 GHz, RBW 300 kHz	-59 dBc (meas.)

 $^{^{\}rm 5)}$ The stop frequency depends on the analog bandwidth of the instrument.

Waveform measurements		
Automatic measurements	measurements on acquired waveforms (input channels), math waveforms, reference waveforms	amplitude, high, low, maximum, minimum, peak-to-peak, mean, RMS, sigma, positive overshoot, negative overshoot, area, rise time, fall time, positive pulse width, negative pulse width, period, frequency, positive duty cycle, negative duty cycle, delay, phase, burst width, pulse count, edge count, pulse train, positive switching, negative switching, cycle area, cycle mean, cycle RMS, cycle sigma, setup, hold, setup/hold time, setup/hold ratio, slew rate rising, slew rate falling, delay to trigger
	gate	delimits the display region evaluated for automatic measurements
	reference levels	user-configurable vertical levels define support structures for automatic measurements
	statistics	displays maximum, minimum, mean, standard deviation and measurement count for each auto- matic measurement
	number of active measurements	16
Cursor measurements	available cursors	up to two cursor sets on screen, each set with two horizontal and two vertical cursors
	target waveforms	acquired waveforms (input channels), math waveforms, reference waveforms, XY diagrams
	operating modes	vertical measurements, horizontal measurements or both; vertical cursors either placed manually or locked to waveform

Waveform math		
General features	number of math equations	up to 5
	number of reference waveforms	up to 4
	sources	channel 1, channel 2, channel 3, channel 4, math waveforms 1 to 4, reference waveforms 1 to 4
Functions	operators	add, subtract, multiply, divide, absolute value, square, square root, integrate, differentiate, \log_{10} , \log_{e} , \log_{2} , reciprocal, invert, lowpass, highpass, rescale (a*x+b)
	filters	lowpass, highpass
	filter types	Gaussian, rectangular
	gate	delimits the display region used for waveform maths

Display characteristics	
Display types	y(t), zoom, spectrum
Display configuration (waveform layout)	The display area can be split into separate diagram areas by dragging and dropping signal icons for the desired waveforms into the R&S®SmartGrid. Each diagram can hold any number of signals. Diagrams can be stacked on top of each other and later accessed via dynamic tabs (Tab 1, etc.).
Signal icons	Each active waveform is represented by a signal icon on the signal bar; the signal icon displays the individual vertical and acquisition settings.
Toolbar	Enables quick access to important functions; allows direct setting of their most common parameters in a simple menu and provides access to more detailed parameter settings in the main menu. The toolbar can be individually configured to include the user's preferred tools.
Upper menu bar	Displays trigger, horizontal and acquisition system settings; allows quick access to these settings.
Main menu	Provides access to all instrument settings in a compact menu structure.
Axis labeling	The x-axis and y-axis are labeled with values and physical unit.
Diagram labeling	Diagrams may be individually labeled with a descriptive, user-defined name.
Diagram layout	The grid, crosshair, axis labeling and diagram labeling can be switched on and off separately.
Persistence	50 ms to 50 s, or infinite
Zoom	vertical and horizontal; touch interface simplifies resize and drag operations on zoom window
Signal colors (waveform coding)	predefined or user-defined color tables for persistence display

History function and segmented me	mory			
Acquisition memory	automatic	automatic setting o	of segment size and sample r	ate
	manual	user-defined setting of segment size and sample rate		e rate
Memory segmentation	function	memory is divided into segments for signal acquisition		uisition
	number of segments	record length	segments 6) (up to)	total memory
		1 kpoints	1048575	1.048 Gpoints
		2 kpoints	524287	1.048 Gpoints
		5 kpoints	262 143	1.310 Gpoints
		10 kpoints	131 071	1.310 Gpoints
		20 kpoints	65 535	1.310 Gpoints
		50 kpoints	32 767	1.638 Gpoints
		100 kpoints	16383	1.638 Gpoints
		200 kpoints	9361	1.872 Gpoints
		500 kpoints	4095	2.047 Gpoints
		1 Mpoints	2113	2.113 Gpoints
		2 Mpoints	1056	2.112 Gpoints
		5 Mpoints	427	2.135 Gpoints
		10 Mpoints	213	2.130 Gpoints
		20 Mpoints	106	2.120 Gpoints
		50 Mpoints	41	2.050 Gpoints
		100 Mpoints	20	2.000 Gpoints
		200 Mpoints	9	1.800 Gpoints
		400 Mpoints	4	1.600 Gpoints
		800 Mpoints7)	2	1.600 Gpoints
	Segmentation is availab analysis.	s available for all analog and digital channels, protocol decoding and spectrum		coding and spectrum
Fast segmented mode	9	•	sition memory without interroons, see "Acquisition system	•
History mode	function	,	s an always-on function and segmented memory.	provides access to past
	timestamp resolution	1 ns		
	history player		aveforms; repetition possible revious segment; numerical	
	analysis options		ts, average all segments, env	· '
	,	, 5		. 0

Inputs and outputs		
Front		
Channel inputs		BNC; for details, see "Vertical system"
	probe interface	autodetection of passive probes, Rohde&Schwarz probe interface for active probes
Trigger input		BNC; for details, see "Trigger system"
	probe interface	autodetection of passive probes
Arbitrary waveform generator outputs (requires R&S®MXO4-B6 option)		BNC; for details, see R&S®MXO4-B6, arbitrary waveform generator, demo lugs and GND lug
Digital channel inputs	D15 to D8, D7 to D0	interfaces for R&S®RT-ZL04 logic probe
Probe compensation output	signal shape	rectangle, $V_{low} = 0 \text{ V}$, $V_{high} = 3.3 \text{ V}$, amplitude 3.3 V (V_{pp}) $\pm 5\%$ (meas.)
	frequency	1 kHz ± 1% (meas.)
Ground jack		connected to ground
USB interfaces		1 x USB 3.1 Gen 1 port, type A, 2 x USB 2.0 high speed port, type A
Rear		
Trigger output		BNC; for details, see "Trigger system"
USB interfaces		2 x USB 3.1 Gen 1 port, type A, 1 x USB 3.1 Gen 1 port, type B
LAN interface		RJ-45 connector, supports 10/100/1000BASE-T

⁶⁾ With R&S®MXO4-B108 memory option. The maximum number of segments depends on the number of active channels and the bit resolution of the acquired data and, therefore, on the acquisition system settings such as decimation mode, use of waveform arithmetics and high-definition (HD) mode. The maximum number of segments without the R&S®MXO4-B108 memory option is limited to 10000.

 $^{^{7)}}$ With R&S°MXO4-B108 memory option.

Inputs and outputs		
External monitor interface		HDMI™, 1920 × 1080 pixel at 60 Hz, output of oscilloscope display
Reference input	connector	BNC
	impedance	50 Ω (nom.)
	input frequency	10 MHz (±20 ppm)
	sensitivity	\geq -10 dBm into 50 Ω , \leq 10 dBm at 10 MHz
Reference output	connector	BNC
	impedance	50 Ω (nom.)
	output signal	10 MHz (specified with timebase accuracy), 8 dBm (nom.)
Security slot		for standard Kensington lock
VESA mounting interface		100 mm × 100 mm VESA standard pattern
Right side		
Ground jack		connected to ground

District		13.3" LC TFT color display with capacitive
Display	type	touchscreen
	resolution	1920 × 1080 pixel (Full HD)
Temperature		
Temperature range	operating temperature range	0°C to +50°C
	storage temperature range	-40°C to +70°C
		in line with MIL-PRF-28800F, section 4.5.5.1.1.1, class 3, tailored to +45°C for operation
Climatic resistance	damp heat	+25°C/+50°C at 85% relative humidity, cyclic, in line with IEC 60068-2-30
Altitude		
Operating		up to 3000 m above sea level
Nonoperating		up to 4600 m above sea level
Mechanical resistance		
Vibration	sinusoidal	5 Hz to 150 Hz, max. 1.8 g at 55 Hz; 0.5 g from 55 Hz to 150 Hz, in line with EN 60068-2-6
		10 Hz to 55 Hz, in line with MIL-PRF-28800F, section 4.5.5.3.2, class 3
	random	$8\ Hz$ to 500 Hz, acceleration 1.2 g (RMS), in line with EN 60068-2-64
		5 Hz to 500 Hz, acceleration 2.058 g (RMS), in line with MIL-PRF-28800F, section 4.5.5.3.1, class 3
Shock		40 g shock spectrum, in line with MIL-STD-8100 method no. 516.6, procedure I
		30 g functional shock, half sine, duration 11 ms, in line with MIL-PRF-28800F, section 4.5.5.4.1
Electromagnetic compatibility (EMC)		
RF emissions		in line with CISPR 11/EN55011, group 1, class A (for a shielded test setup); instrument complies with emission requirement stipulated by EN55011, EN61326-1 and EN61326-2-1 class A, making it suitable for use in industrial environments
Immunity		in line with IEC/EN61326-1 table 2, immunity te requirements for equipment used in industrial environments ⁸⁾
Certifications		VDE, _c CSA _{us} , KC
Calibration interval		1 year

 $^{^{8)}}$ Test criterion is displayed noise level within ± 1 div for an input sensitivity of 5 mV/div.

General data		
Power supply		
AC supply		$100~V$ to $240~V~\pm10~\%$ at $50~Hz$ to $60~Hz$ and $400~Hz~\pm5~\%,$ max. $2.3~A$ to $1.3~A,$ in line with MIL-PRF-28800F, section 3.5
Power consumption		max. 210 W
Safety		in line with IEC 61010-1, EN 61010-1, CAN/CSA-C22.2 No. 61010-1, UL 61010-1
Mechanical data		
Dimensions	$W \times H \times D$	414 mm \times 279 mm \times 162 mm (16.3 in \times 10.99 in \times 6.38 in)
Weight	without options, nominal	6.0 kg (13.23 lb)
Rackmount height	with R&S®ZZA-MXO4 rackmount kit	6 HU

ORDERING INFORMATION

Designation	Туре	Order No.
R&S®MXO 4 series, base unit		
Oscilloscope, 200 MHz, 4 channels	R&S®MXO 4	1335.5050.04
Base unit (including standard accessories: 700 MHz passive probe (10:1) per channel, accessories	bag, quick start guide, power co	ord)
Choose your bandwidth upgrade		
Upgrade of R&S®MXO 4 series oscilloscopes to 350 MHz bandwidth	R&S®MXO4-B243	1335.4276.02
Upgrade of R&S®MXO 4 series oscilloscopes to 500 MHz bandwidth	R&S®MXO4-B245	1335.4299.02
Upgrade of R&S®MXO 4 series oscilloscopes to 1 GHz bandwidth	R&S®MXO4-B2410	1335.4318.02
Upgrade of R&S®MXO 4 series oscilloscopes to 1.5 GHz bandwidth	R&S®MXO4-B2415	1335.4330.02
Choose your options		
Mixed signal option with 16 digital channels, for R&S®MXO 4 series oscilloscopes	R&S®MXO4-B1	1335.4130.02
Arbitrary waveform generator, 100 MHz, 2 analog channels	R&S®MXO4-B6	1335.4147.02
Memory upgrade to 800 Mpoints on 2 channels	R&S®MXO4-B108	1335.5772.02
Low speed serial triggering and decoding (I2C/SPI/UART/RS-232/RS-422/RS-485)	R&S®MXO4-K510	1335.5195.02
Automotive serial triggering and decoding (CAN/CAN FD/CAN XL 1)/LIN 1))	R&S®MXO4-K520	1335.5550.02
Frequency response analysis	R&S®MXO4-K36	1335.5572.02
Application bundle with the following options: R&S°MXO4-K510, R&S°MXO4-K520, R&S°MXO4-K36, R&S°MXO4-B6	R&S®MXO4-PK1	1335.5237.02
Choose your additional probes		
Passive probes: single-ended		
700 MHz, 10 MΩ, 10:1, 400 V, 9.5 pF, 2.5 mm	R&S®RT-ZP11	1803.0005.02
500 MHz, 10 MΩ, 10:1, 400 V, 9.5 pF, 2.5 mm	R&S®RT-ZP10	1409.7550.00
500 MHz, 10 MΩ, 10:1, 300 V, 10 pF, 5 mm	R&S®RT-ZP05S	1333.2401.02
$38~\text{MHz}, 1~\text{M}\Omega, 1:1, 55~\text{V}, 39~\text{pF}, 2.5~\text{mm}$	R&S®RT-ZP1X	1333.1370.02
Active broadband probes: single-ended		
1.0 GHz, 10:1, 1 M Ω , BNC interface	R&S®RT-ZS10L	1333.0815.02
1.0 GHz, 1 M Ω , Rohde & Schwarz probe interface	R&S®RT-ZS10E	1418.7007.02
1.0 GHz, 1 M Ω , R&S $^{\circ}$ ProbeMeter, micro button, Rohde&Schwarz probe interface	R&S®RT-ZS10	1410.4080.02
1.5 GHz, 1 M Ω , R&S $^{\circ}$ ProbeMeter, micro button, Rohde&Schwarz probe interface	R&S®RT-ZS20	1410.3502.02
Active broadband probes: differential		
1.0 GHz, 1 M Ω , R&S°ProbeMeter, micro button, including 10:1 external attenuator, 1 M Ω , 70 V DC, 46 V AC (peak), Rohde&Schwarz probe interface	R&S®RT-ZD10	1410.4715.02
$1.5~\text{GHz},1~\text{M}\Omega,\text{R\&S}^{\circ}\text{ProbeMeter},\text{micro}$ button, Rohde & Schwarz probe interface	R&S®RT-ZD20	1410.4409.02
Power rail probe		
2.0 GHz, 1:1, 50 k Ω , ± 0.85 V, ± 60 V offset, Rohde & Schwarz probe interface	R&S®RT-ZPR20	1800.5006.02

¹⁾ Available with future firmware release.

Designation	Туре	Order No.
High voltage probes: passive	7,00	
250 MHz, 100:1, 100 MΩ, 850 V, 6.5 pF	R&S®RT-ZH03	1333.0873.02
400 MHz, 100:1, 50 MΩ, 1000 V, 7.5 pF	R&S®RT-ZH10	1409.7720.02
400 MHz, 1000:1, 50 MΩ, 1000 V, 7.5 pF	R&S®RT-ZH11	1409.7737.02
High voltage probes: differential		
100 MHz, 100:1/1000:1, 8 MΩ, 1000 V (RMS) CAT III, BNC interface	R&S®RT-ZD01	1422.0703.02
200 MHz, 250:1/25:1, 5 MΩ, 750 V (peak), 300 V (RMS) CAT III, Rohde&Schwarz probe interface	R&S®RT-ZHD07	1800.2307.02
100 MHz, 500:1/50:1, 10 MΩ, 1500 V (peak), 1000 V (RMS) CAT III, Rohde&Schwarz probe interface	R&S®RT-ZHD15	1800.2107.02
200 MHz, 500:1/50:1, 10 MΩ, 1500 V (peak), 1000 V (RMS) CAT III, Rohde&Schwarz probe interface	R&S®RT-ZHD16	1800.2207.02
100 MHz, 1000:1/100:1, 40 MΩ, 6000 V (peak), 1000 V (RMS) CAT III, Rohde&Schwarz probe interface	R&S®RT-ZHD60	1800.2007.02
Current probes		
20 kHz, AC/DC, 0.01 V/A and 0.001 V/A, ±200 A and ±2000 A, BNC interface	R&S®RT-ZC02	1333.0850.02
100 kHz, AC/DC, 0.1 V/A, 30 A, BNC interface	R&S®RT-ZC03	1333.0844.02
2 MHz, AC/DC, 0.01 V/A, 500 A (RMS), Rohde & Schwarz probe interface	R&S®RT-ZC05B	1409.8204.02
10 MHz, AC/DC, 0.01 V/A, 150 A (RMS), BNC interface	R&S®RT-ZC10	1409.7750K02
10 MHz, AC/DC, 0.01 V/A, 150 A (RMS), Rohde&Schwarz probe interface	R&S®RT-ZC10B	1409.8210.02
50 MHz, AC/DC, 0.1 V/A, 30 A (RMS), Rohde&Schwarz probe interface	R&S®RT-ZC15B	1409.8227.02
100 MHz, AC/DC, 0.1 V/A, 30 A (RMS), BNC interface	R&S®RT-ZC20	1409.7766K02
100 MHz, AC/DC, 0.1 V/A, 30 A (RMS), Rohde & Schwarz probe interface	R&S®RT-ZC20B	1409.8233.02
120 MHz, AC/DC, 1 V/A, 5 A (RMS), BNC interface	R&S®RT-ZC30	1409.7772K02
EMC near-field probe set		
Compact probe set for E and H near-field measurements, 30 MHz to 3 GHz	R&S®HZ-15	1147.2736.02
Logic probe ²⁾		
400 MHz logic probe, 8 channels	R&S®RT-ZL04	1333.0721.02
Probe accessories		
Accessory set for R&S°RT-ZP11 passive probe (2.5 mm probe tip)	R&S®RT-ZA1	1409.7566.00
Probe power supply for R&S®RT-ZC10/-ZC20/-ZC30 probes	R&S®RT-ZA13	1409.7789.02
External attenuator 10:1, 2.0 GHz, 1.3 pF, 60 V DC, 42.4 V AC (peak), for R&S*RT-ZD20/-ZD30 probes	R&S®RT-ZA15	1410.4744.02
Probe pouch	R&S®RT-ZA19	
Power deskew and calibration test fixture	R&S®RT-ZF20	1800.0004.02
3D positioner with central tensioning knob for easy clamping and positioning of probes (span width: 200 mm, clamping range: 15 mm)	R&S®RT-ZA1P	1326.3641.02
Choose your accessories		
Front cover	R&S®MXO4-Z1	1335.4360.02
Soft case	R&S®MXO4-Z3	1335.5589.02
Transit case	R&S®MXO4-Z4	1335.5595.02
19" rackmount kit, 6 HU	R&S®ZZA-MXO4	1335.5108.02
VESA mounting interface	100 mm × 100 mn pattern	n VESA standard

Warranty		
Base unit		3 years
All other items 3)		1 year
Service options		
Extended warranty, one year	R&S®WE1	Please contact
Extended warranty, two years	R&S®WE2	
Extended warranty with calibration coverage, one year	R&S®CW1	your local
Extended warranty with calibration coverage, two years	R&S®CW2	Rohde & Schwarz sales office.
Extended warranty with accredited calibration coverage, one year	R&S®AW1	
Extended warranty with accredited calibration coverage, two years	R&S®AW2	

²⁾ The R&S®MXO4-B1 mixed signal option contains two R&S®RT-ZL04 logic probes.

The terms HDMI and HDMI High-Definition Multimedia Interface, and the HDMI Logo are trademarks or registered trademarks of HDMI Licensing, LLC in the United States and other countries.

³⁾ For options installed, the remaining base unit warranty applies if longer than 1 year. Exception: all batteries have a 1 year warranty.

Service at Rohde & Schwarz You're in great hands

- ▶ Worldwide
- Local and personalized
- Customized and flexible
- ► Uncompromising quality
- ► Long-term dependability



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The Rohde&Schwarz technology group is among the trail-blazers when it comes to paving the way for a safer and connected world with its leading solutions in test&measurement, technology systems and networks&cybersecurity. Founded more than 85 years ago, the group is a reliable partner for industry and government customers around the globe. The independent company is headquartered in Munich, Germany and has an extensive sales and service network with locations in more than 70 countries.

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Sustainable product design

- ► Environmental compatibility and eco-footprint
- ► Energy efficiency and low emissions
- ► Longevity and optimized total cost of ownership

Certified Quality Management

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